

20th International Workshop on
Electron Cyclotron Resonance Ion Sources

Space Charge Compensation Measurements for ECRIS beams

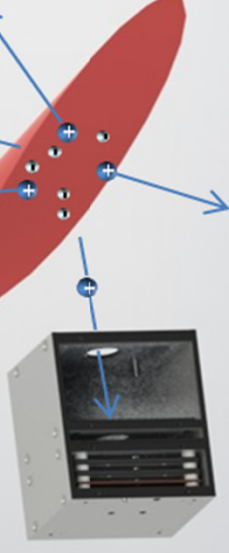
Daniel Winklehner

D. Leitner, G. Machiccone, F. Marti, D. Cole, L. Tobos

NSCL/MSU

Outline:

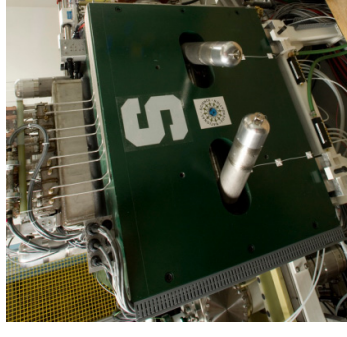
- Introduction
- Hardware
- Measurements
- Discussion



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UNIVERSITY

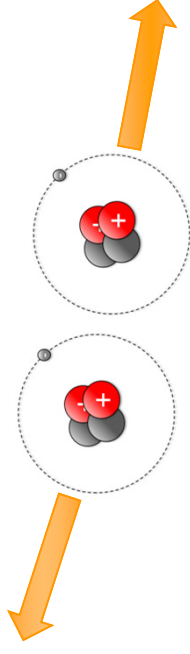
ECRIS and LEBT

- Current ECR ions sources like Venus and SuSI are able to create up to 20 mA of beam
- Next (4th) generation ECRIS even more!
- These are regimes, where space-charge effects become important factors for:
 - Beam size
 - Beam quality
 - Transmission
- Especially in the Low Energy Beam Transport (LEBT) system before the analyzing magnet
- Have to consider SC in design and simulations
- What is space-charge?



For next generation
ECRIS see other talks
at this workshop

Space Charge (SC)



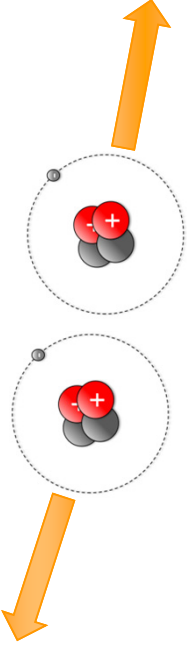
$$E_r = \frac{I}{2\pi\epsilon_0\beta c} \frac{r}{a^2}$$

$$\Phi(r) = \Delta\phi \left(1 + 2 \ln \frac{b}{a} - \frac{r^2}{a^2} \right) \quad \Phi(r) = 2\Delta\phi \ln \left(\frac{b}{r} \right)$$

$$\Delta\phi = \frac{I \cdot (1 - f_e)}{4\pi\epsilon_0\beta c}$$

Space Charge (SC)

- Coulomb repulsion between beam ions
- Collective effect – creates self-field of the beam
- Defocusing term in Hill's equation – beam growth
- Simple model of the beam: Uniformly charged cylinder



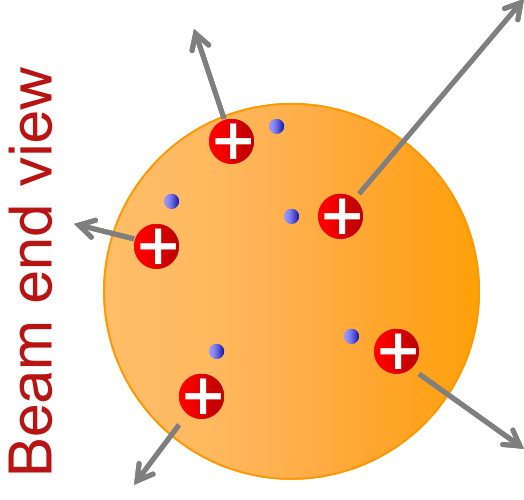
- Radial electric field: $E_r = \frac{I}{2\pi\epsilon_0\beta c} \frac{r}{a^2}$
- Radial Potential: $\Phi(r) = \Delta\phi \left(1 + 2\ln \frac{b}{a} - \frac{r^2}{a^2} \right)$; $\Phi(r) = 2\Delta\phi \ln \left(\frac{b}{r} \right)$; with $\Delta\phi = \frac{I \cdot (1 - f_e)}{4\pi\epsilon_0\beta c}$

(a = beam radius, b = beam line radius, I = beam current, βc = velocity)

- If the beam were to experience the full self-field at all times bad for beam transport of high current beams! – Luckily: Compensation

Space Charge Compensation (SCC)

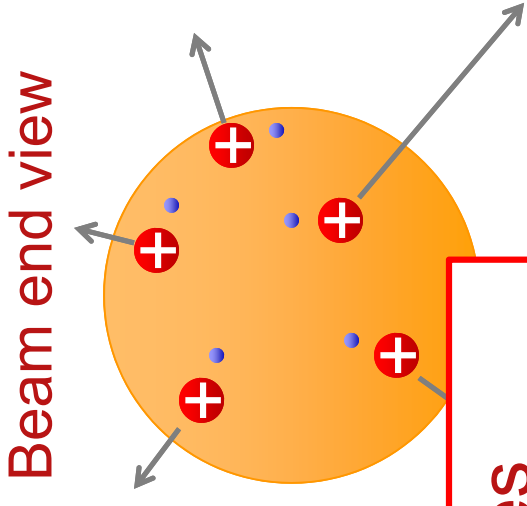
- As the beam goes through the residual gas in the beam line – interaction:
 - Collisions
 - Charge exchange
- Electrons are separated from gas atoms/molecules
- electrons are trapped in beam potential, ions are expelled
- Electrons effectively lower the beam potential
- Process is steady-state, governed by rates of electrons created and captured and electrons leaving the beam.
- From Soloshenko[#]:



$$\Delta\phi = \sqrt{3\mathcal{L}} \left(\frac{M}{m} \right)^{1/2} \left(\frac{\varphi_i}{V_0} \right)^{1/2} n_+^{1/2} \left(\frac{1}{n_0\sigma_e} + \frac{v_+\sigma_i r_0}{2v_i\sigma_e} \right)^{1/2} \cdot e$$

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- Process $\Delta\phi$ increases when n_0 decreases
- From Soloshenko#:

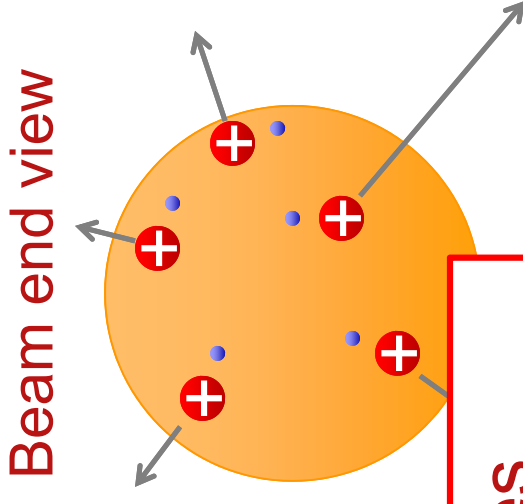


Dominates for low pressures
 $\Delta\phi$ increases when n_0 decreases

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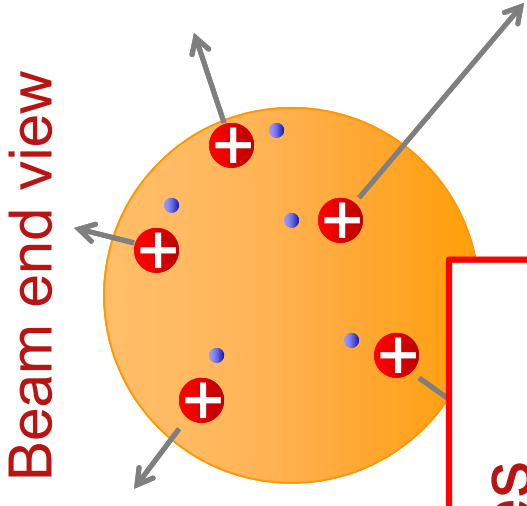


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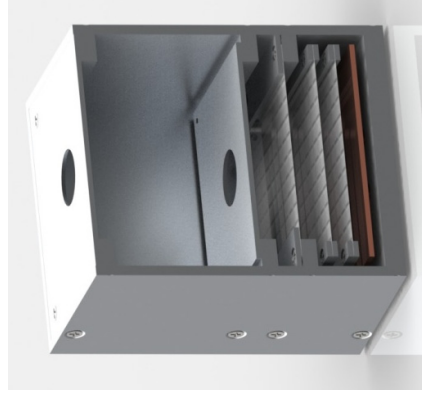
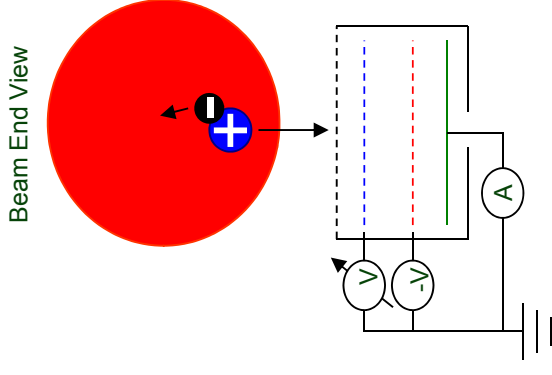
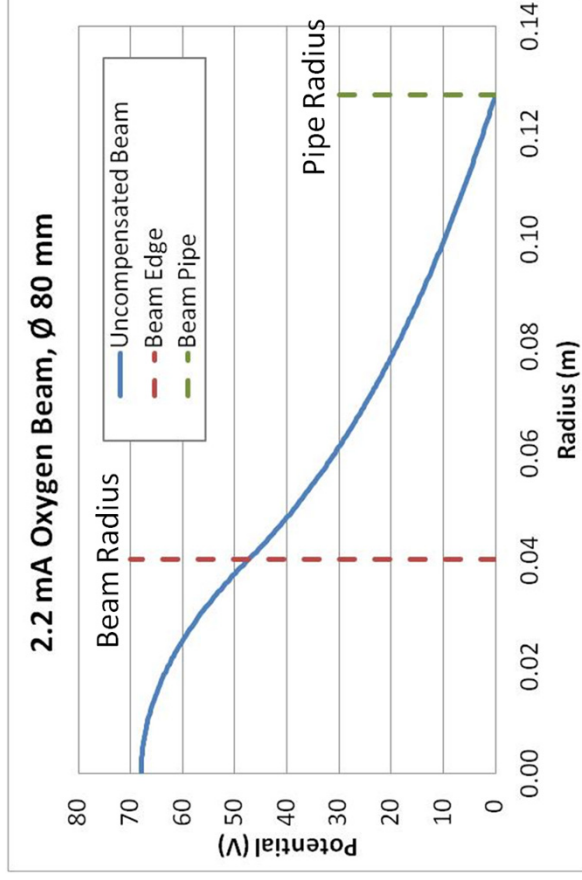


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Measuring Space Charge Compensation

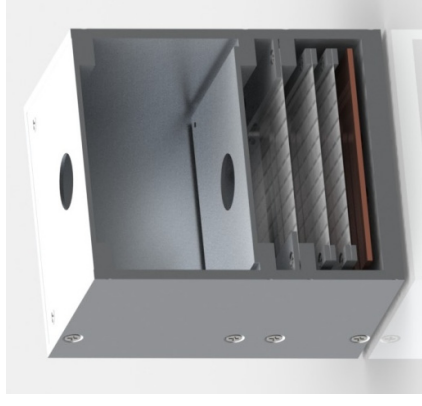
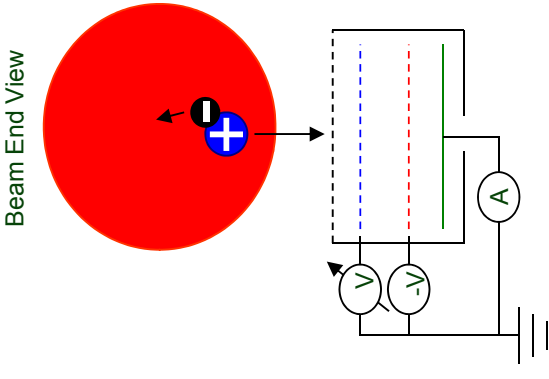
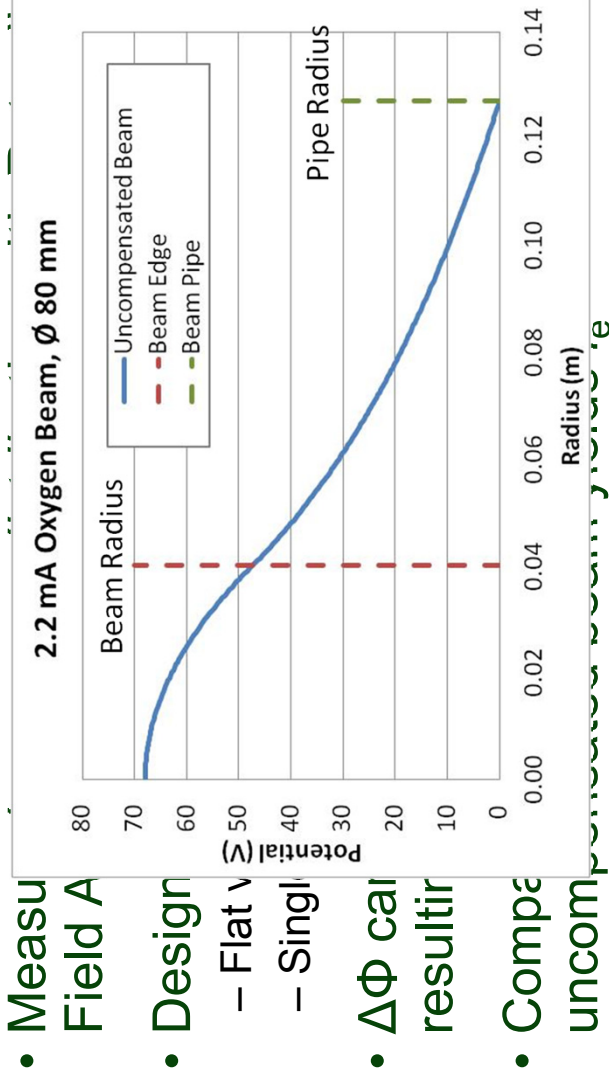
$$\overline{E}_{kin} = \frac{5}{2} k_B T \longrightarrow \sim 65 \text{ meV}$$



Measuring Space Charge Compensation

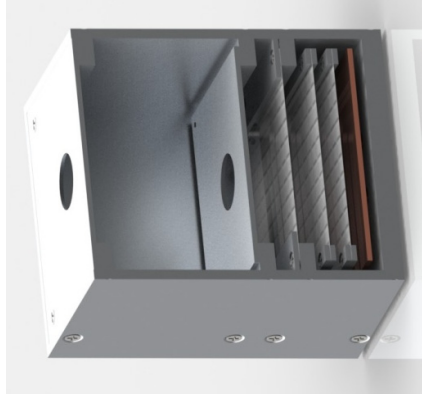
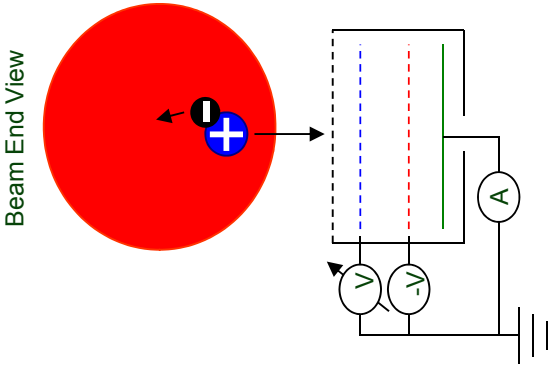
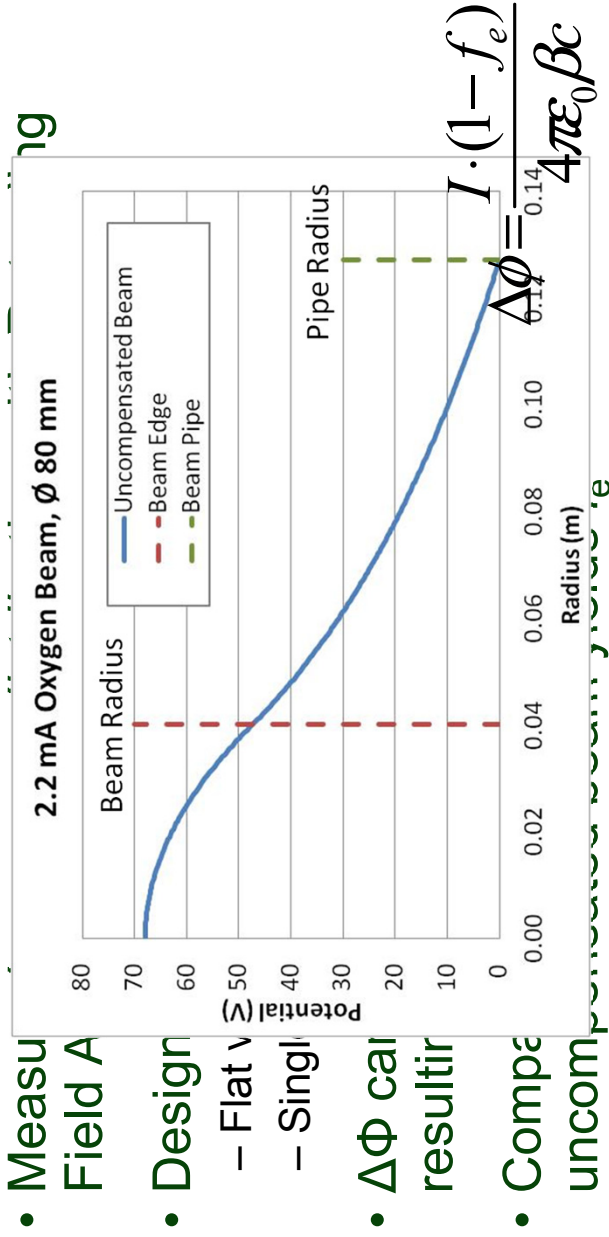
- Secondary Ions have energy depending on distance from beam center at time of ionization
- Assumptions:
 - Very low initial kinetic energy $\bar{E}_{kin} = \frac{5}{2} k_B T \rightarrow \sim 65 \text{ meV}$ (dimolecular gas, $T = 293 \text{ K}$)
 - Secondary ions do not gain significant energy through collisions

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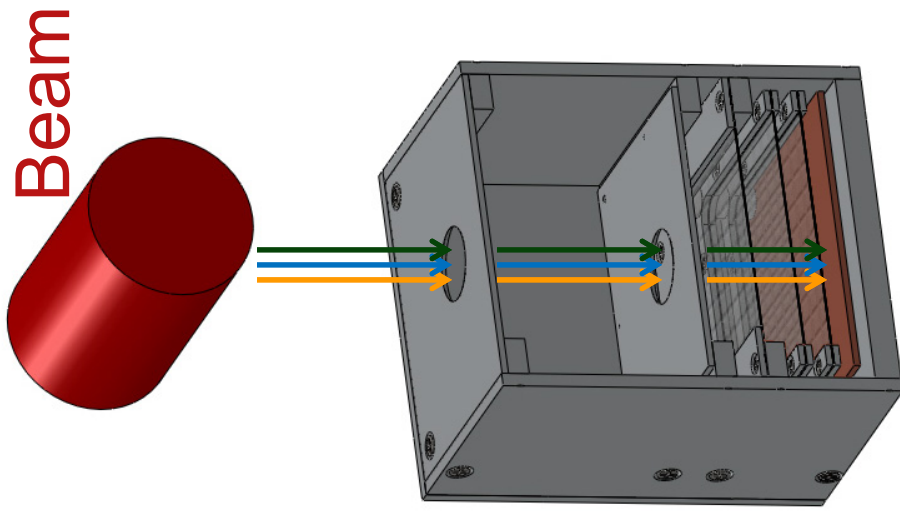
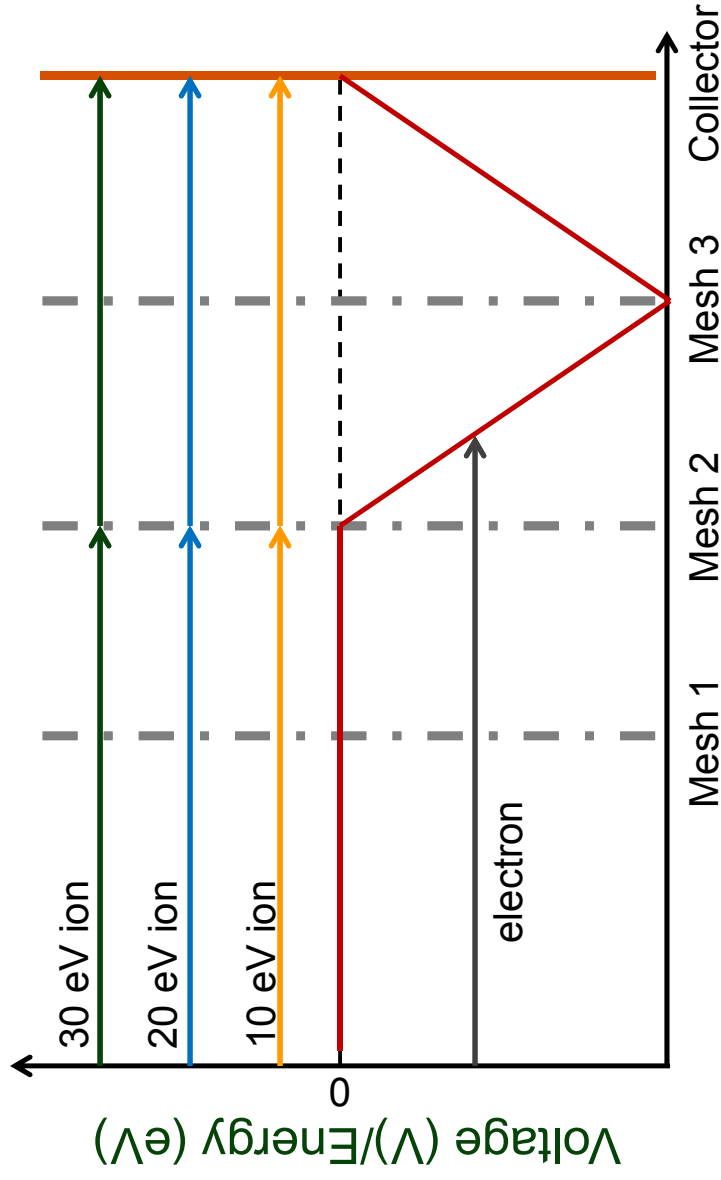
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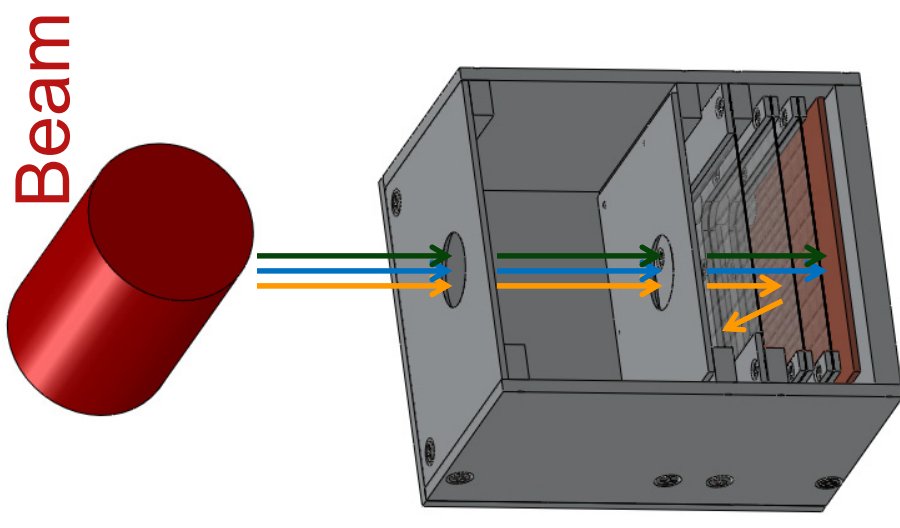
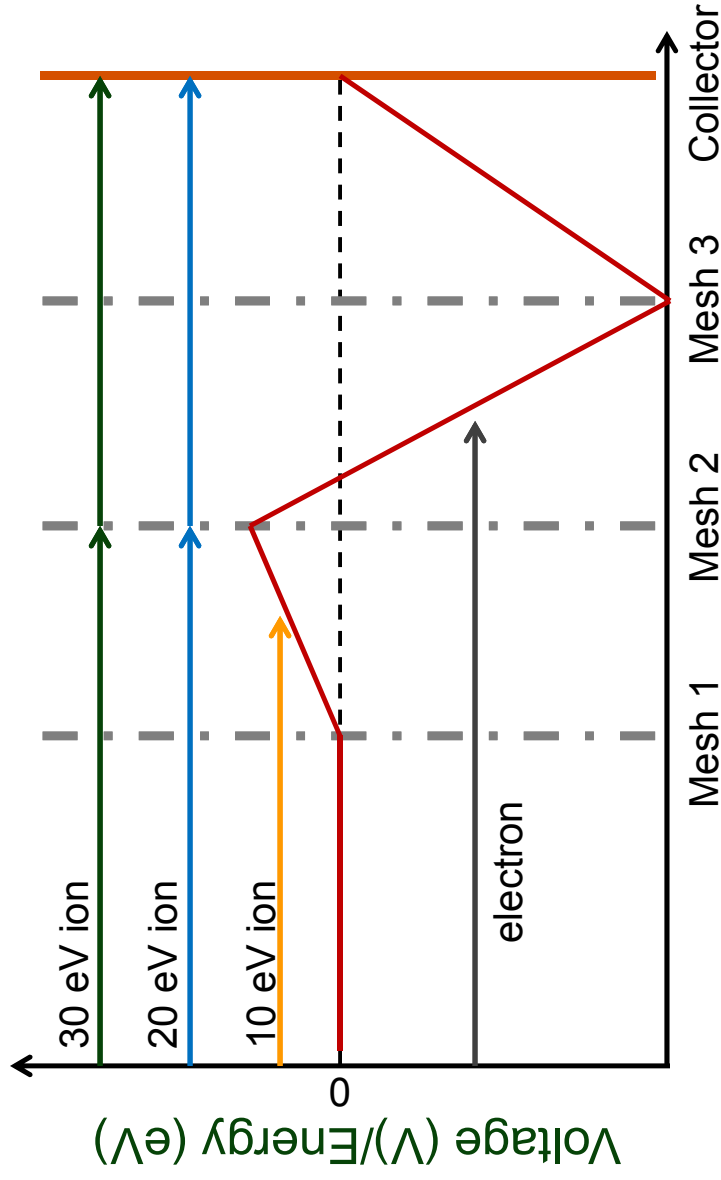
Retarding Field Analyzer (RFA)

- Mesh 1 voltage = 0 V
- Mesh 2 voltage = 0 V
- Mesh 3 voltage = - 450 V



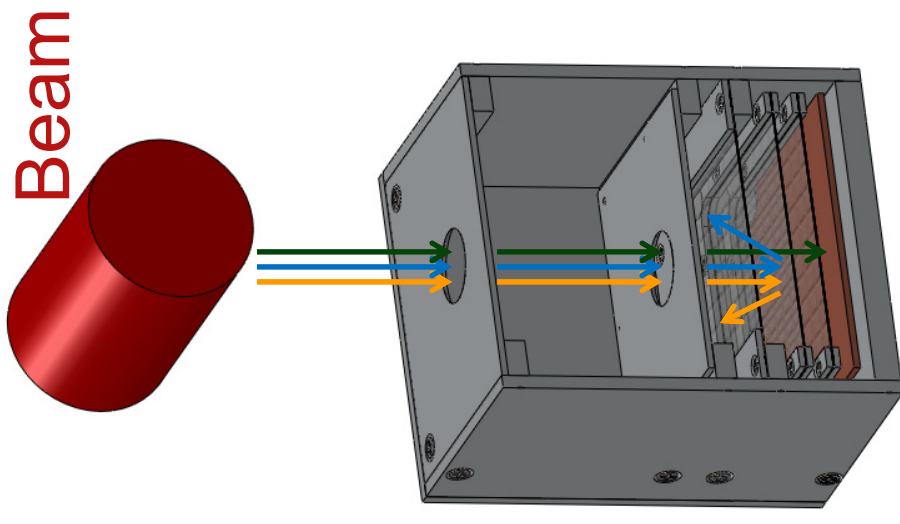
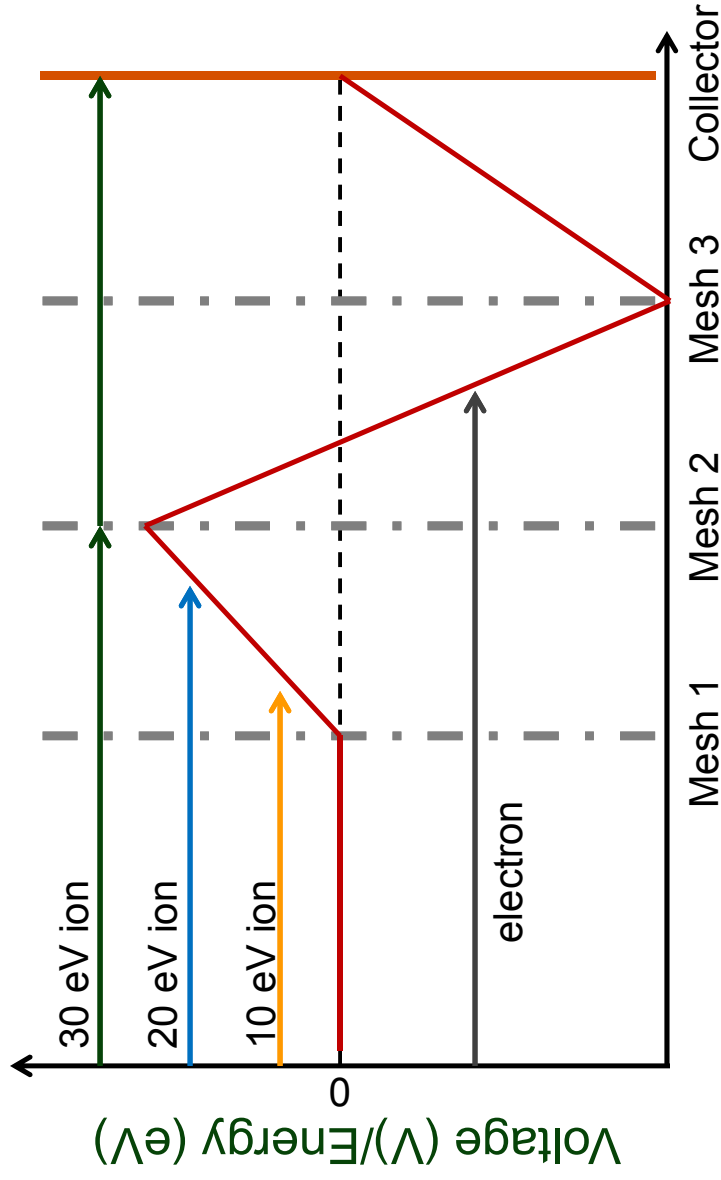
Retarding Field Analyzer (RFA)

- Mesh 1 voltage = 0 V
- Mesh 2 voltage = 15 V
- Mesh 3 voltage = - 450 V



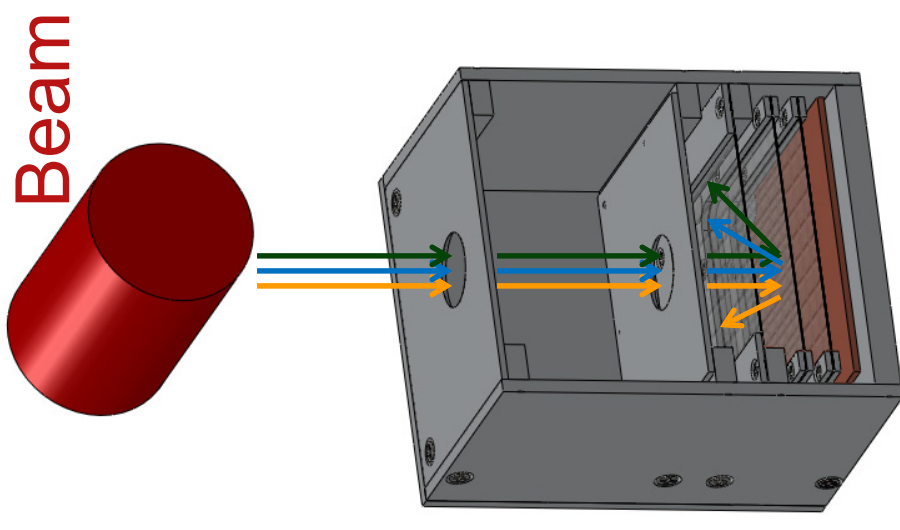
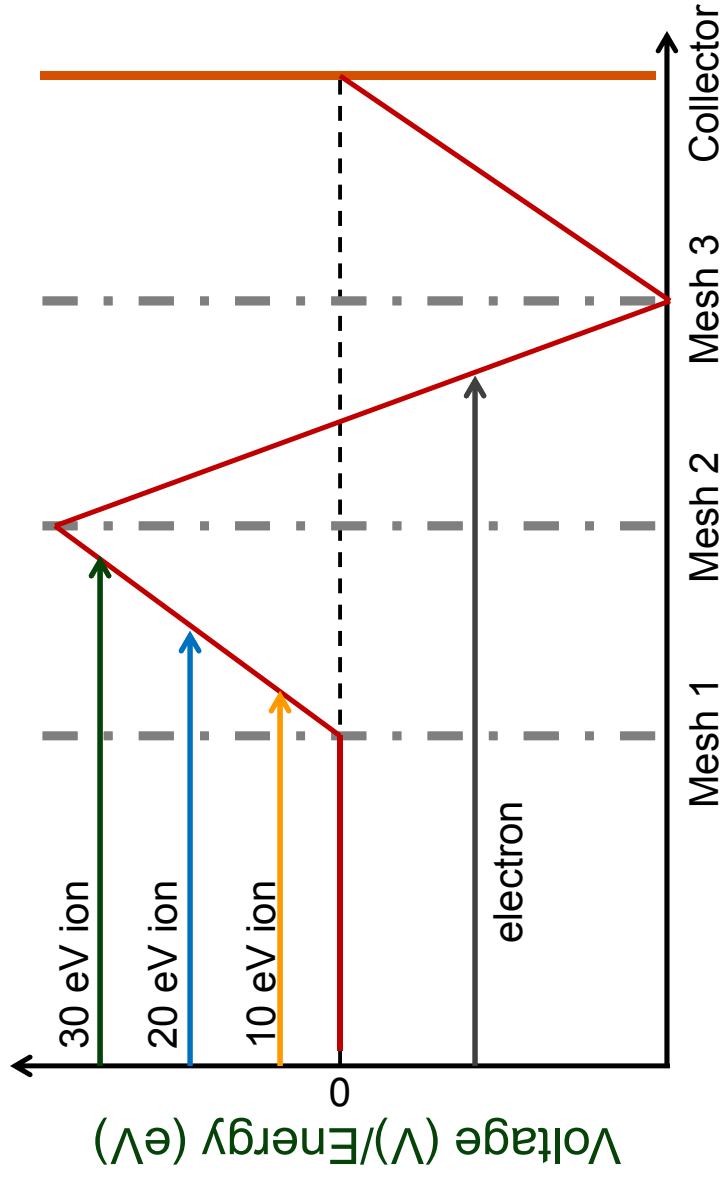
Retarding Field Analyzer (RFA)

- Mesh 1 voltage = 0 V
- Mesh 2 voltage = 25 V
- Mesh 3 voltage = - 450 V

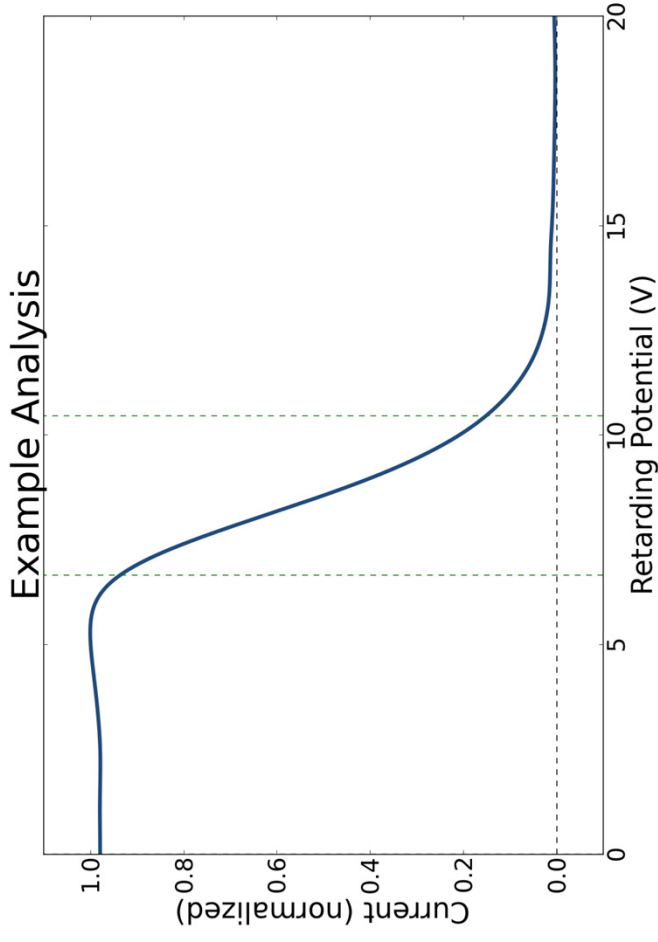


Retarding Field Analyzer (RFA)

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- Mesh 2 voltage = 35 V
- Mesh 3 voltage = - 450 V



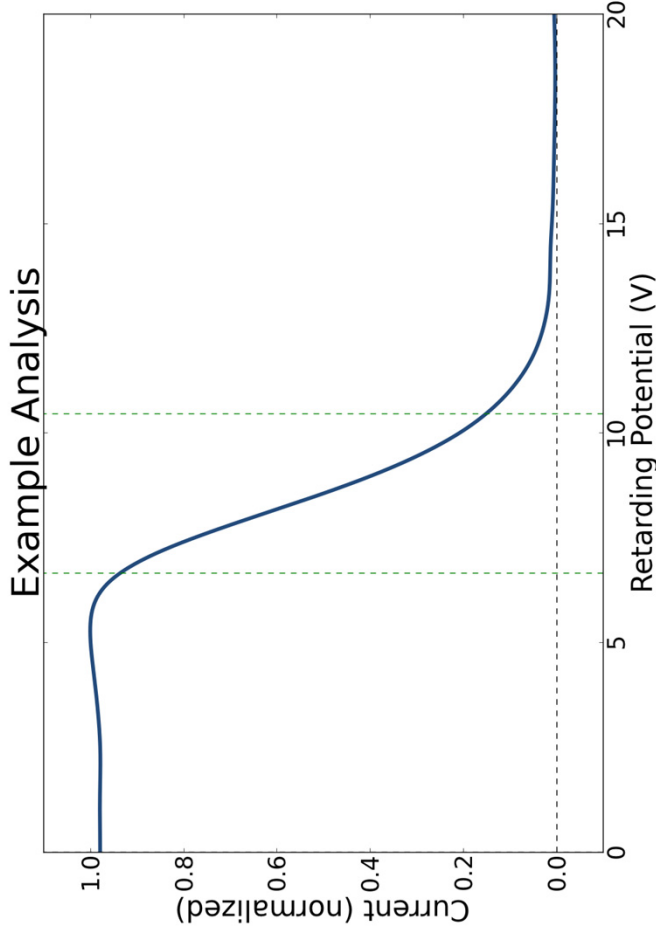
Analysis (LEDA source example)



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- Typical RFA spectrum
- 2 Methods of analysis:
 - Take dI/dV and use base width (subtract 1.2 V for detector resolution)
 - Fit the graph with 3 straight lines to obtain Φ_{center} and Φ_{edge}
- Result:
 - Meth. 1: $\Delta\Phi \sim 4.6$ V
Neutralization $\sim 78.4\%$
 - Meth. 2: $\Delta\Phi \sim 3.8$ V
Neutralization $\sim 83.0\%$

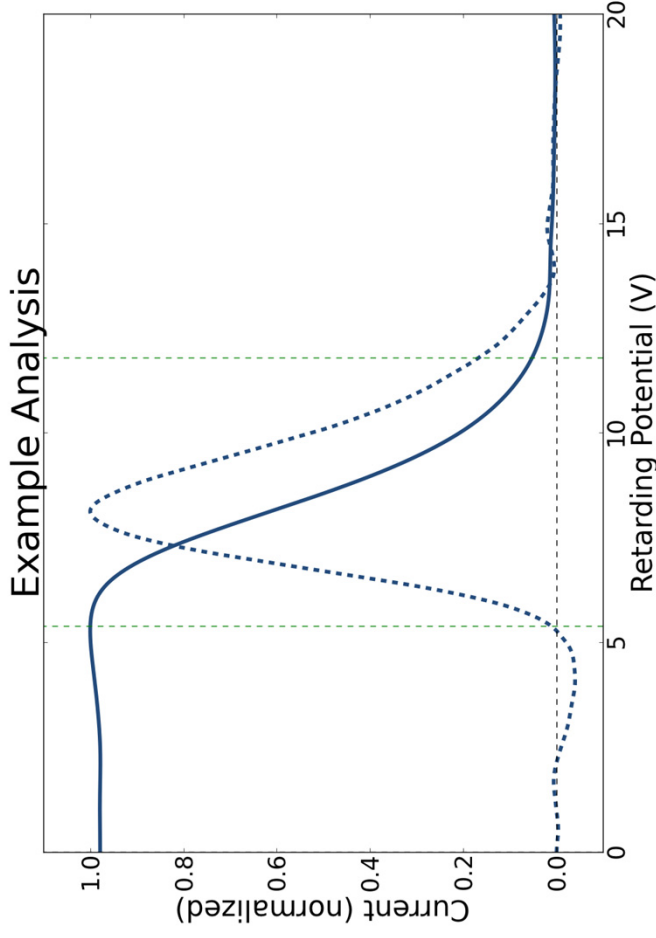
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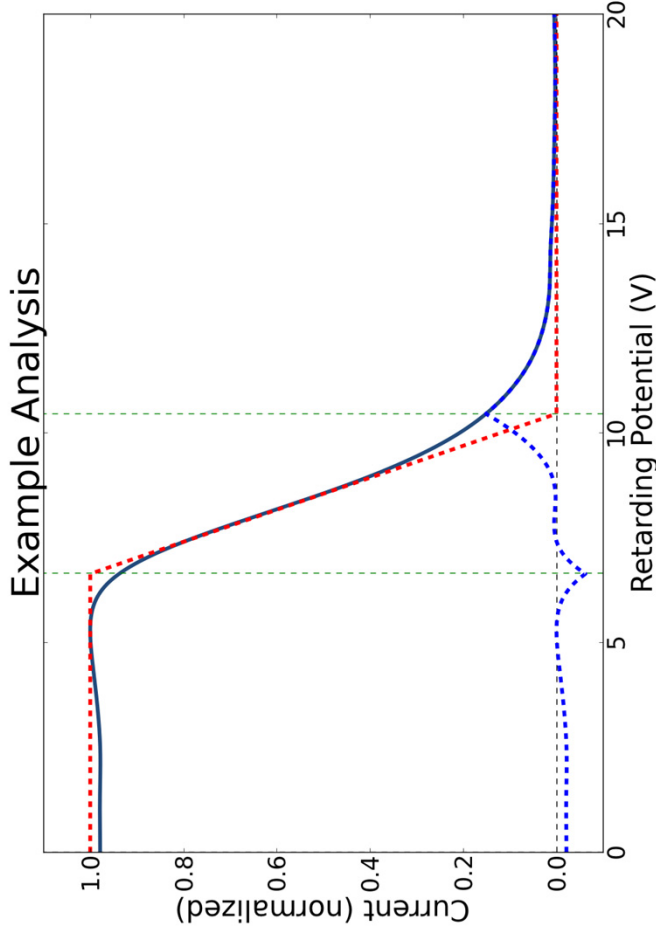
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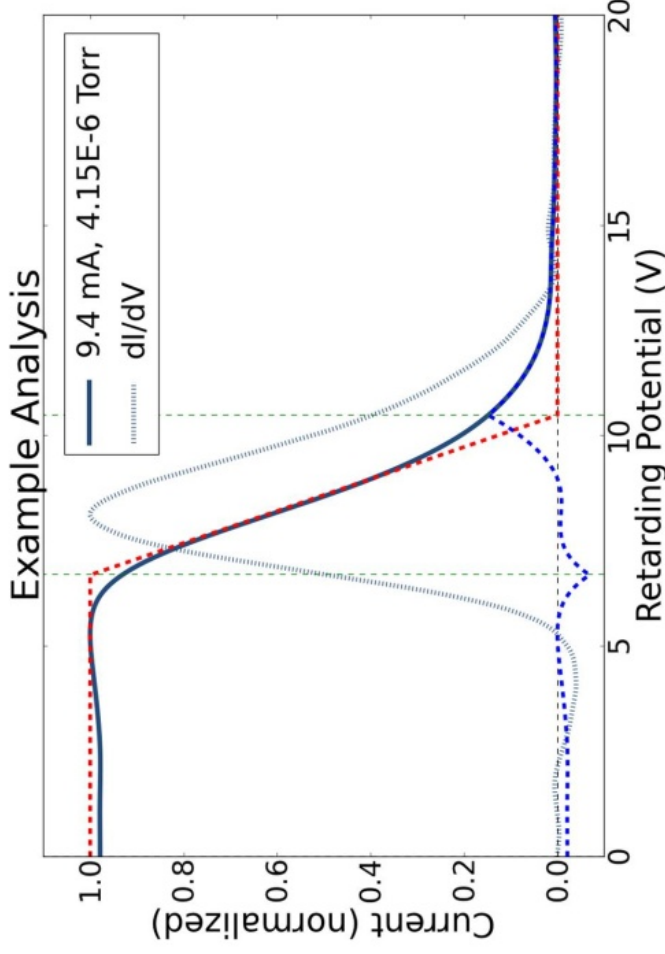
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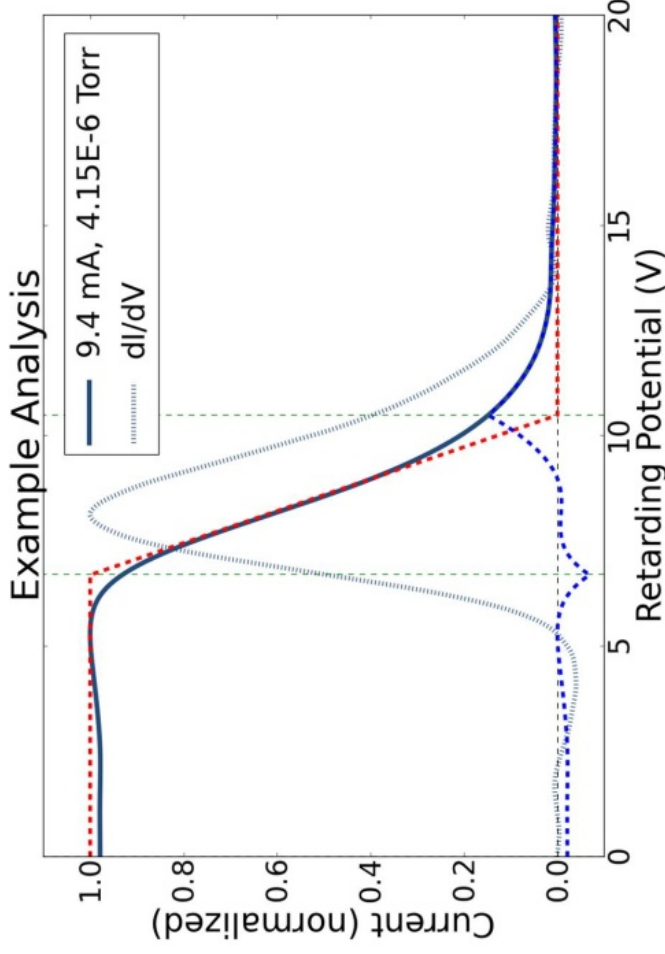
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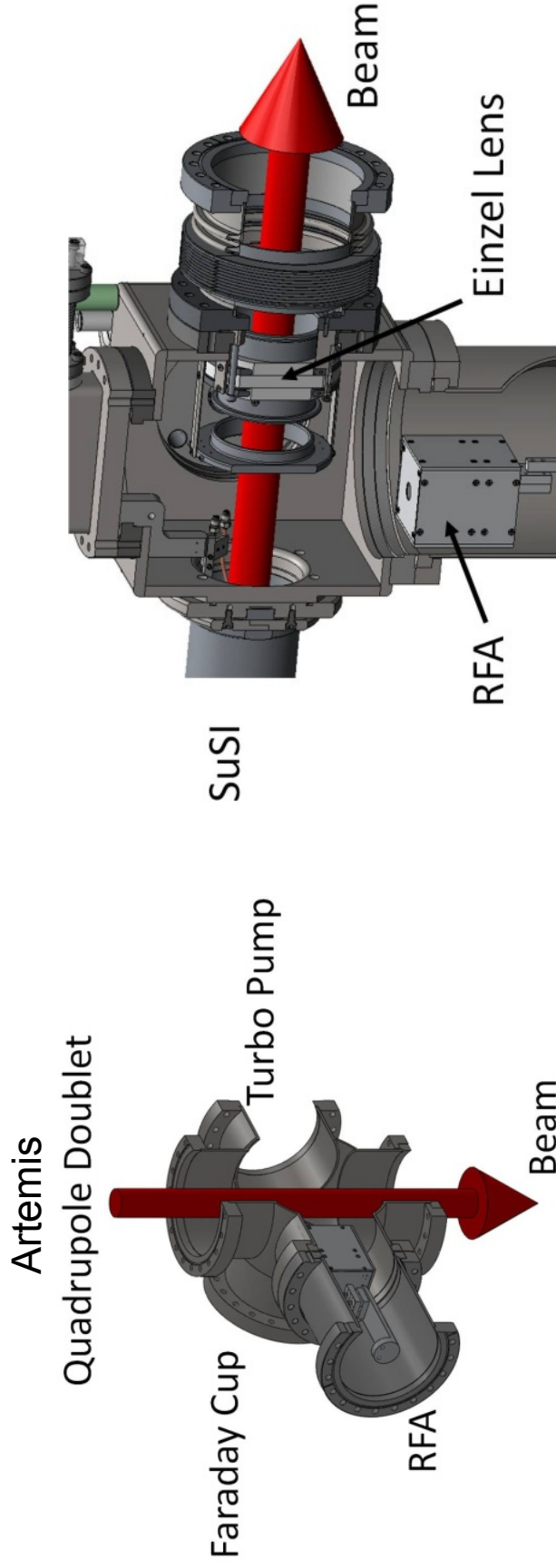
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$$\Delta\phi = \frac{I \cdot (1 - f)}{4\pi \cdot \epsilon_0 \cdot \beta c}$$

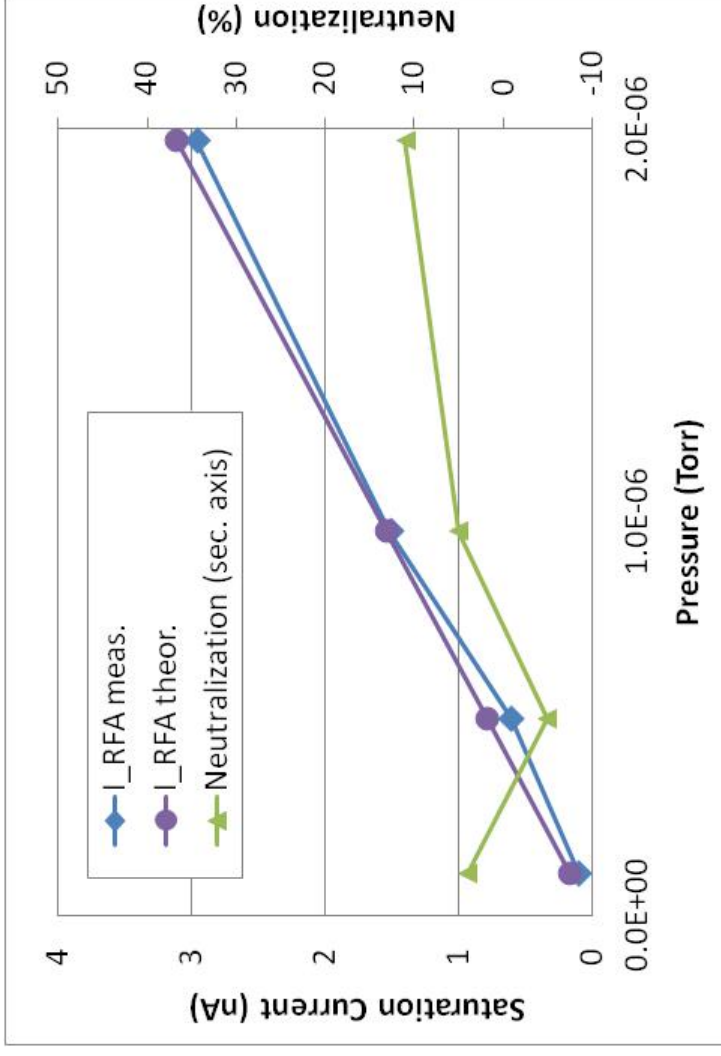
RFA Measurement Positions (Artemis A, SuSI, LEDA)



- Artemis A: The RFA is located between source and the analyzing magnet after an electrostatic quadrupole doublet.
- SuSI: RFA is located in diagnostic box 1 ~46 cm after the plasma aperture
- LEDA injector source: RFA is located in a diagnostic box ~50 cm after the plasma aperture

Artemis Measurements

- First measurements
- Only one aperture in Retarding Field Analyzer
- Electrostatic Quadrupole settings to maximize current in Retarding Field Analyzer
- Beam current measured with Faraday Cup = 550 μA
- Saturation Current in agreement with theoretical prediction from continuity equation with 40% transmission

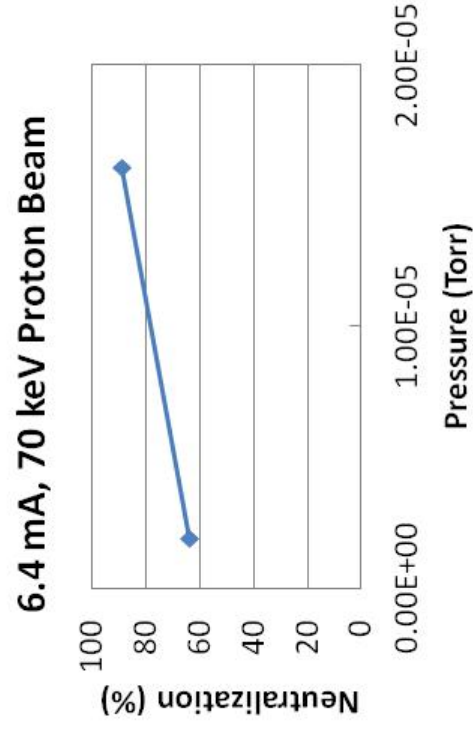
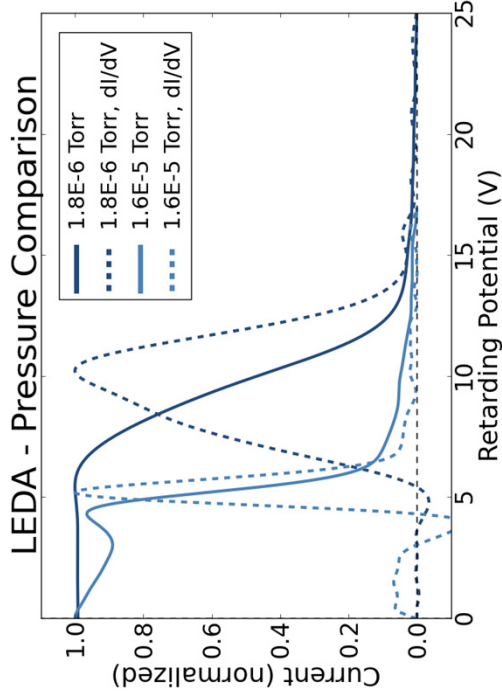
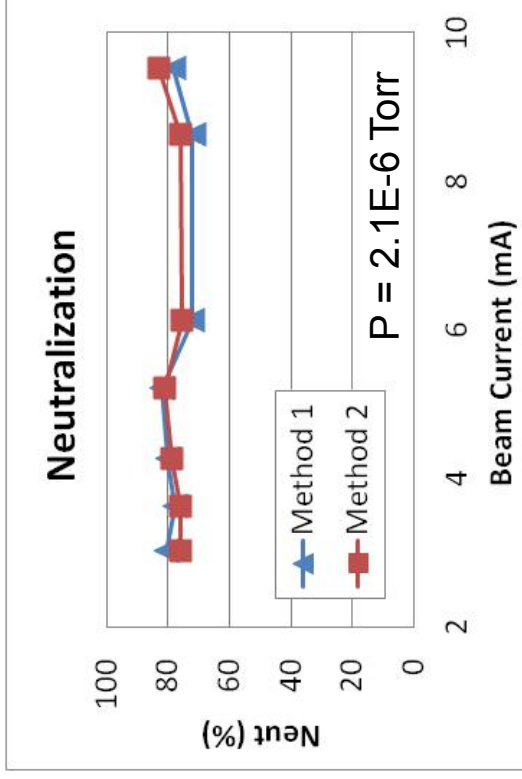
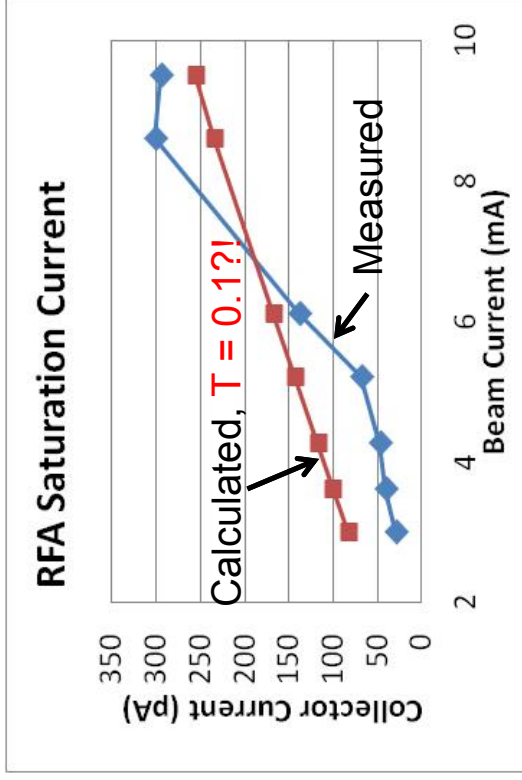


$$(I_{RFA})_s = \frac{r_a^2 \cdot T \cdot I \cdot (\sum n_g \sigma_i)}{2d} ; T = 0.4$$

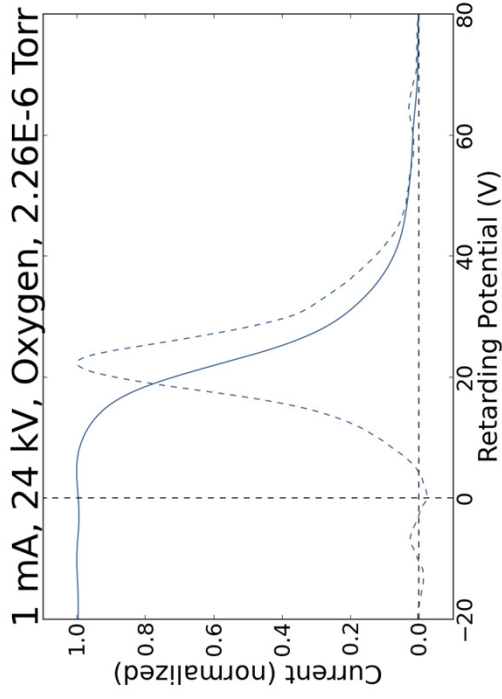
- More or less **0% neutralization**, maybe slightly increasing tendency

LEDA Measurements

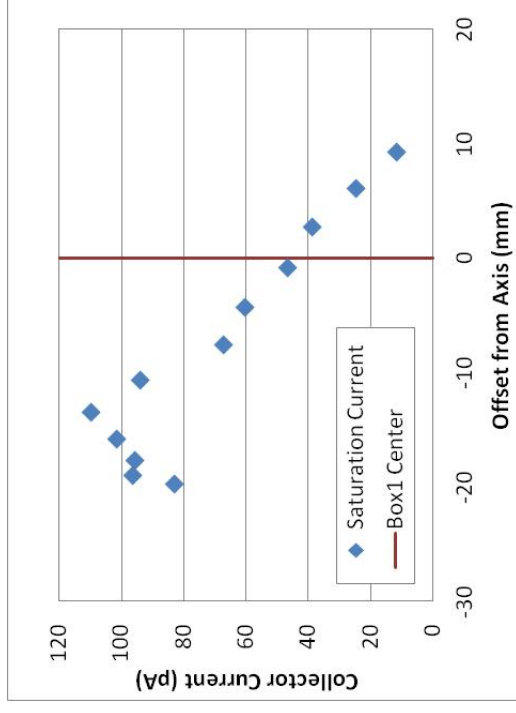
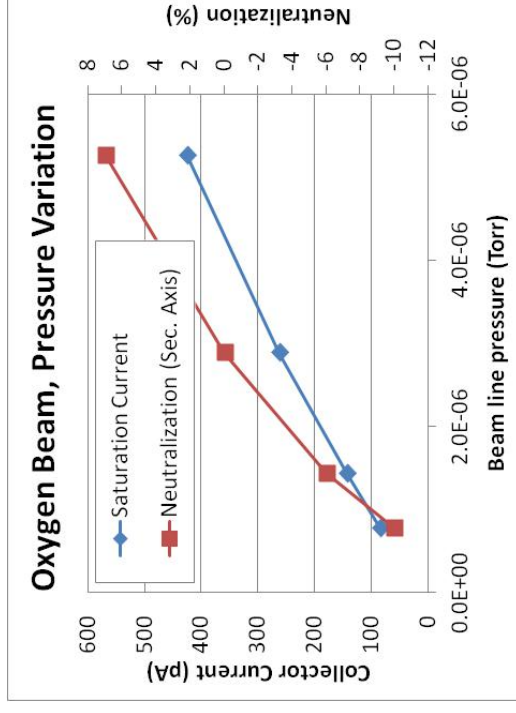
2 Aperture Collimation



SuSI Measurements

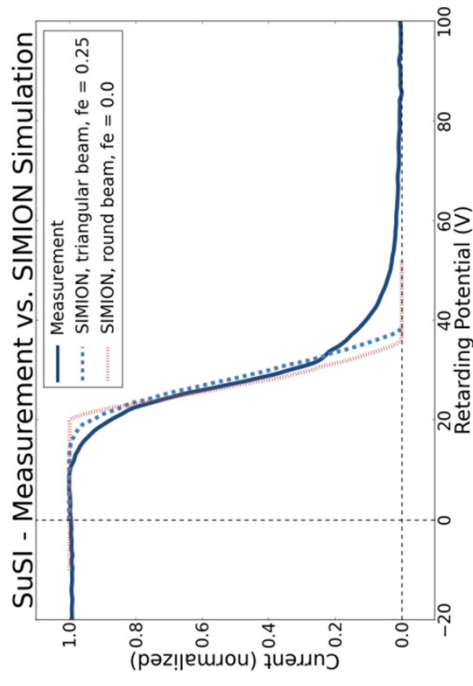
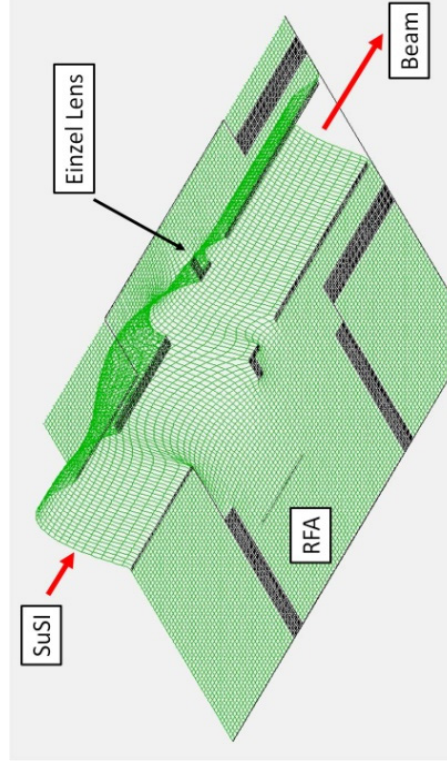
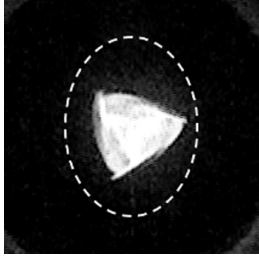
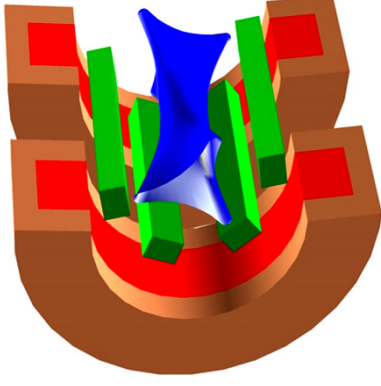


- $\Delta\Phi_{\text{measured}} > \Delta\Phi_{\text{uncompensated}}$
 \rightarrow "negative" neutralization ✗
- Moving Retarding Field Analyzer perpendicular to beam: Asymmetry



Complexity of Measuring ECR neutralization

- Triangular Beams
- Multiple Species
 - ionization cross-sections depend on charge state
- Beam lines not infinite pipes concentric with beam!
 - > Longitudinal v-component
- Simulations show large difference in obtained neutralization value for triangular or round beams...



Summary and Conclusions



- A new Retarding Field Analyzer was built at the NSCL
- Extensive Simulations have been conducted to determine the feasibility of the design and the theoretical resolution.
- Preliminary measurements have been carried out at three different sources (SuSI, Artemis and LEDA injector source), all three currently at the NSCL.
- The measurements showed trends that neutralization increases with pressure and/or beam current, which is in accord with previous results by other groups.
- **These measurements also suggest, that in the current low energy beam line configurations of SuSI and Artemis only low neutralization can be observed.**
- But: Some behaviors unexplained → future work

Outlook

- **Measure Beam Cross-Sections** with Quartz or KBr beam viewer
- As the neutralization can change throughout the LEBT, **alternative positions for the retarding field analyzer** will be explored in order to obtain a more complete picture of neutralization in ECR LEBTs
- Investigate asymmetric beams further through simulation (and possibly running ECR sources with and without sextupole).
- Further investigate current reduction with 2nd aperture.
- Build/borrow? a small electron gun to do calibration measurements in order to confirm the theoretical accuracy and resolution.



Acknowledgements

- Thanks to the NSCL electrical engineering department and the machine shop for continuous support!
- Thanks to the Michigan Institute for Plasma Science and Engineering (MIPSE) for their support!
- Thanks to Guillaume Machicoane, Felix Marti, Dallas Cole, and Larry Tobos for letting me “play” with their ECR sources :o)



And thank you for your attention... Questions?